

Vanderbilt

Ricky Cadena, "Low-Energy Ion-Induced Single-Event Burnout in Gallium Oxide Schottky Diodes"

Sajal Islam, "Device modification brings SEB threshold enhancement in β -Ga₂O₃ Schottky Diodes"

Aditha Senarath, "Heavy ion-induced single-event effects in vertical GaN diodes"

Stefania Esquer, "Single event functional interrupt (SEFI) characterization of the Armv7-M instruction set architecture"

Bella Wynocker, "Random Telegraph Noise and Radiation Response of 80 nm Vertical Charge-Trapping NAND Flash Memory Devices with SiON Tunneling Oxide"

Grant Mayberry, "Defect Generation and Dynamics in Wide-Bandgap Semiconductor Materials"

Xuyi Luo, "Low-frequency noise and DLTS in *n-p-n* Si bipolar junction transistors irradiated with Si ions"

Xun Li, "Irradiation- and Bias-Stress-Induced Charge Trapping and Gate Leakage in AlGa_N/Ga_N HEMTs"

Zixiang Guo, "Total-Ionizing-Dose Effects in IGZO Thin-Film Transistors with SiO₂ Oxygen-Penetration Layers"

Tianfang Liu, "Proton Total Ionizing Dose Effects in Ga_N FinFETs"

Ohio State

Quinn Shua, "Traps and Radiation Effects in AlGaO Schottky Diodes and Al₂O₃/Ga₂O₃ MIS Capacitors"

Penn State

Farshid Reza, "Modeling swift ion irradiation in Ga_N/Al_N/AlGa_N by molecular dynamics"

Alex Hauck, "Threshold defect formation and properties in Ga_N/Al_N/AlGa_N"

Mahjabin Mahfuz, "TEM analysis of SHI irradiation induced structural defects in Ga_N"

Yixin Xiong, "Design and Fabrication of Ga_N Device Test Structures for Collaborative Research on Radiation Effects"

Nate Martin, "Effects of Gamma Irradiation on GaN devices"

Jianan Song, "Transient Current Induced by Heavy Ion Single Event in Field-Plate and Super-Heterojunction GaN Devices"

Elijah Allridge, "NZFMR, EDMR, EPR Hardware for GaN Studies"

CMU

Renuka Hyderkhan, "High resolution X-ray diffraction to characterize radiation induced defects and strain in GaN epitaxial structures"

Duke

Md Sazzadur Rahman, "IETS on GaN HEMTs"

Md Sazzadur Rahman, "AC transconductance and conductance techniques to investigate defects in GaN HEMTs"

U. Iowa

Joe Sink, "Simulation of EDMR and NZFMR in GaN Devices for Detection of Radiation Induced Defects"